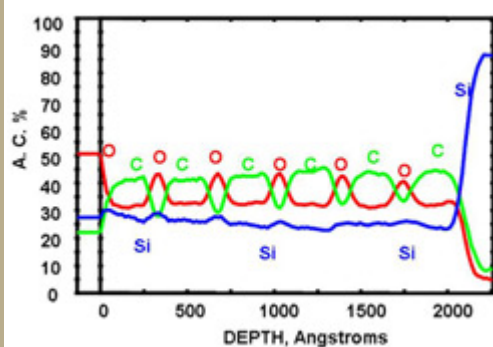


Auger - Film, particle and defect composition



Auger - Film, particle and defect composition



Instruments

- Phi 670 FE Auger Scanning Auger Microprobe

Applications

- Surface Composition Analysis
- Elemental Mapping
- Film composition with depth (with ion sputter)

Technical Specifications

- 0.1 μm spatial resolution

For information or to arrange a demonstration please contact the New Pioneers in Surface Analysis Technology:

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